

<b>Notic of Referenc s Cit d</b>	Application/Control No. 09/764,112	Applicant(s)/Patent Under Reexamination LEE ET AL.	
	Examiner Kenneth A Parker	Art Unit 2871	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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	N	JP 05307160 A	11-1993	Japan	TANAKA et al.	G02F 01/13
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**NON-PATENT DOCUMENTS**

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